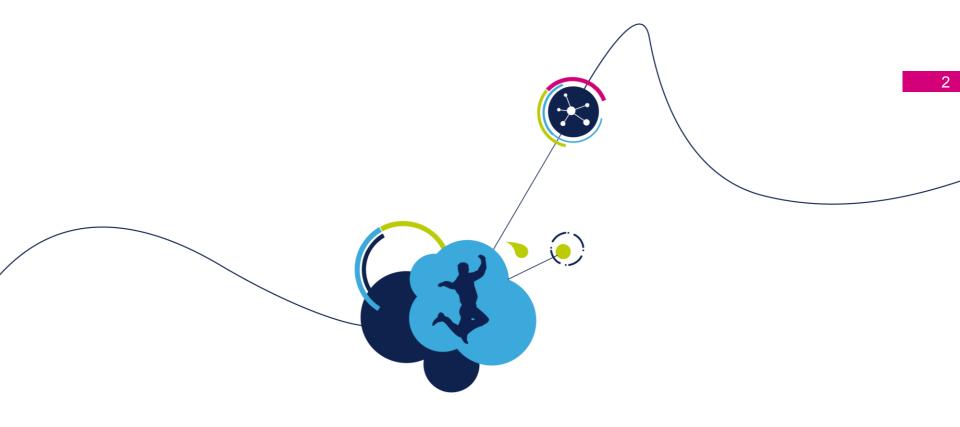
The FD-SOI technology for very high-speed and energy efficient SoCs

FD-SC

Giorgio Cesana STMicroelectronics

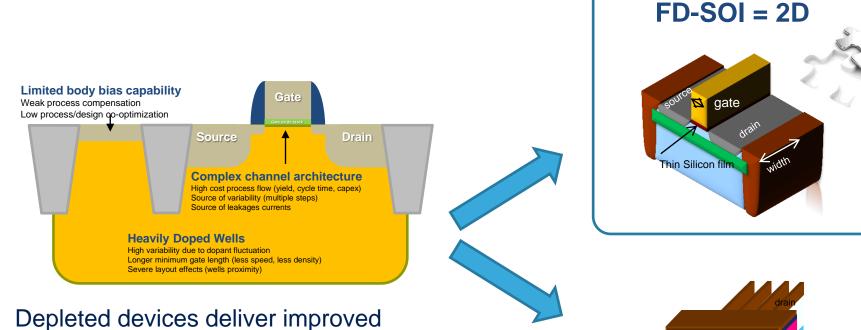




FD-SOI Technology



Bulk Transistor Reaching Limits at 20nm



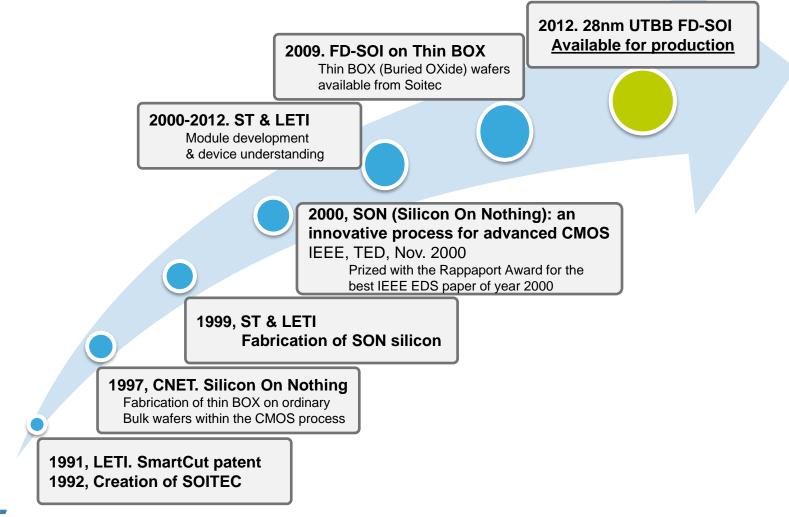
electrostatic control and device scalability

drain tig source gate

FinFET = 3D

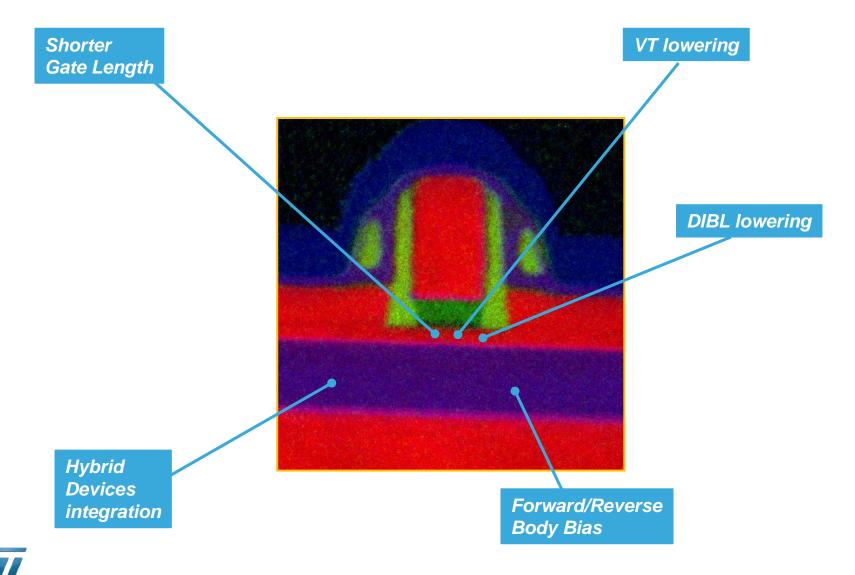


UTBB FD-SOI, A Long R&D Success Story





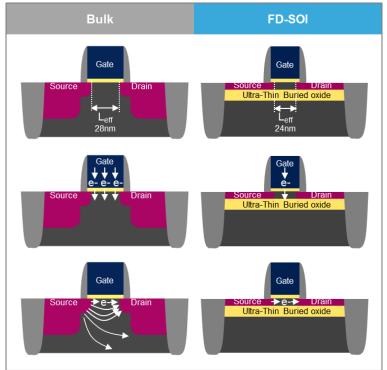
28FDSOI Transistor Summary



life.guamente

Efficient FD-SOI Transistors

- FD-SOI enables better transistor electrostatics
 - Enabling faster operation at low voltage, leading to better energy efficiency
 - Improving transistor behavior, especially at low supply, enabling ultra-low-voltage operation
 - Reducing transistor variability sources
- FD-SOI has a shorter channel length
 - 28nm FD-SOI is in reality a **24nm** technology!
- FD-SOI has lower leakage current
 - Lower channel leakage current
 - Carriers efficiently confined from source to drain
 - Thicker gate dielectrics, leading to lower gate leakage
 - Enabling ultra low power SRAM memories
 - Leakage current is less sensitive to temperature with FD-SOI





FD-SOI The best technology choice

Superior and flexible technology

- Û
- FD-SOI transistors are faster, cooler, simpler
- Outstanding power efficiency across all use cases
- Efficiency at all levels: CPU, logic, Memories, Analog
- Manufacturing infrastructure and process reuse
- Improved reliability

Enhanced design options



- Very large operating range for the same design
- Back-biasing as a flexible and powerful optimization
- Ultra-wide range DVFS
- Enhanced efficiency of multi-core processing
- Easier design than FinFET

Gives your SOC competitive advantages

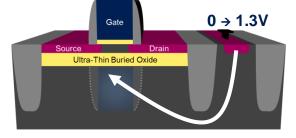
- Costs: chip-level and/or system-level (e.g. cost of cooling)
- Thermal power dissipation (TDP)
- Extended battery life
- Computing Power / Speed / Reactivity
- Reliability
- Time-to-Market



Forward Body Biasing (FBB)

A very reasonable effort for extremely worthwhile benefits

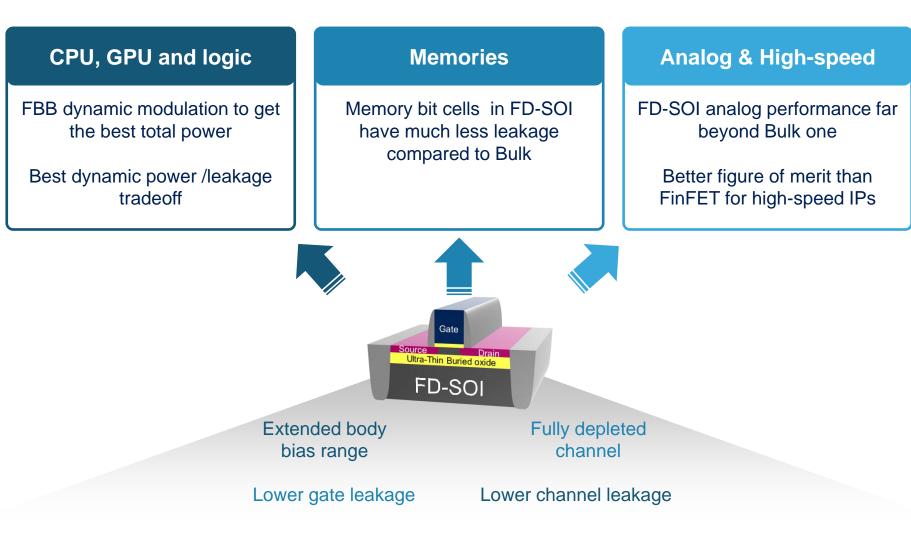
- An extremely powerful and flexible concept in FD-SOI to :
 - Boost performance
 - Optimize passive and dynamic power consumption
 - Cancel out process variations and extract optimal behavior from all parts



 Comparatively easy to implement – if you've ever done DVFS you'll have no difficulty with Body Biasing

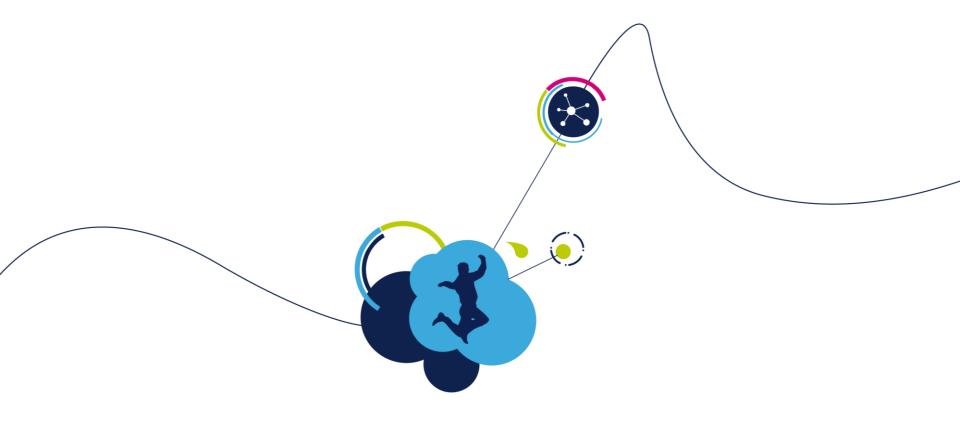


FD-SOI: Efficiency at all levels



Better transistor electrostatics

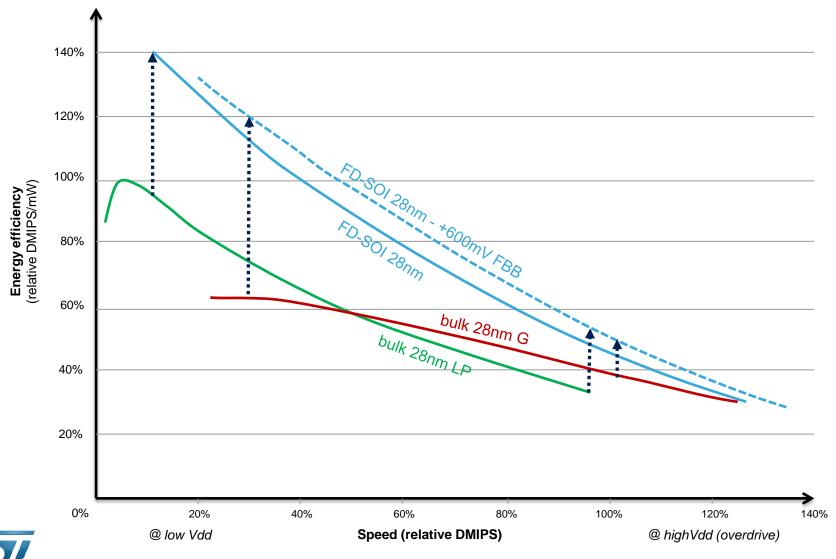




FD-SƏI Energy Efficiency



28nm FD-SOI Best in class efficiency 11



The FD-SOI technology for very high-speed and energy efficient SoCs July 2014

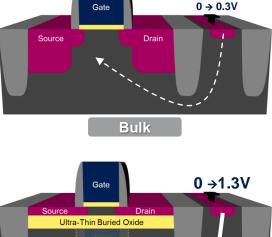
life.augmented

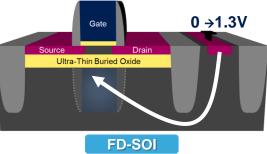
FD-SOI: The FBB advantage

- What is Body Biasing?
 - A voltage is applied to the substrate (or body).
 - When voltage is positive, it is called Forward Body Biasing, or FBB
- Why FBB is much more efficient in FD-SOI?
 - The Insulator layer (UTTB) prevents the parasitic effects that normally appear during the body biasing
 - This allows much wider range of biasing compared to Bulk
 - FBB can be modulated dynamically during the transistor operation and the transitions are transparent to the SW

FBB benefits

- Performance boost
- Reduce power consumption at a given performance requirement
- Process compensation reducing the margins to be taken at design
- · Easy to implement: seamless inclusion in the EDA flow

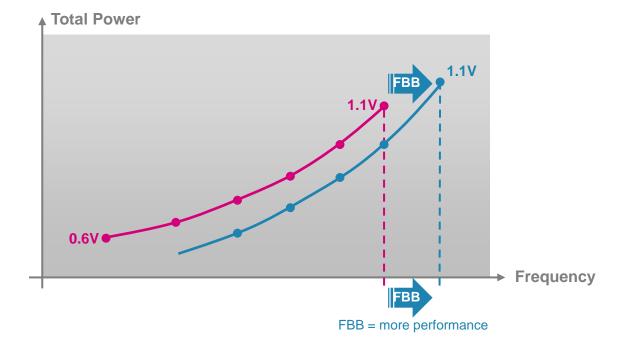




FBB for performance boost **13**

FBB provides performance boost when voltage can't be increased

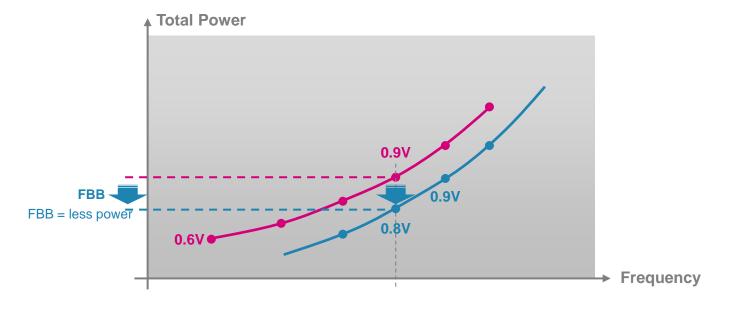
- Limited impact on dynamic power, no impact on voltage drops
- \rightarrow More efficient performance increase than turning the voltage
- Impact on leakage at high temperature
- \rightarrow Back into 28G range but leakage can be turned off anytime by removing FBB



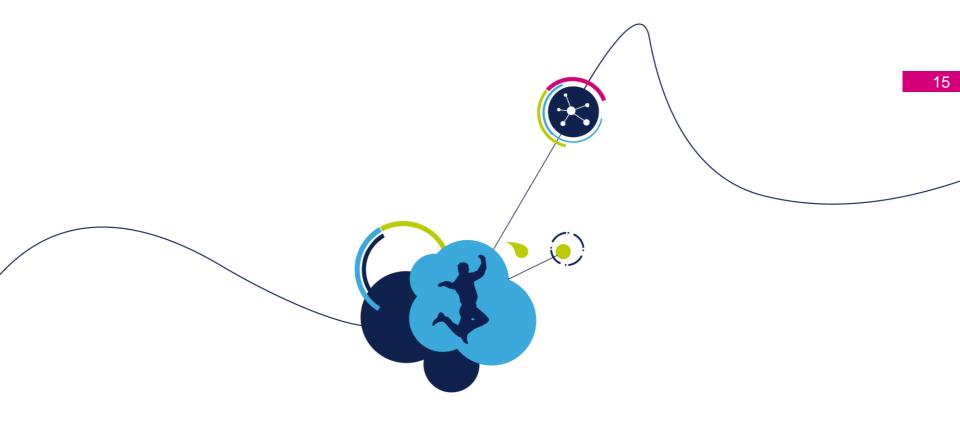


FBB improves power efficiency

- FBB improve the power efficiency at a given frequency
 - Limited impact on leakage, slightly higher than without FBB
 - Drastically decrease dynamic power



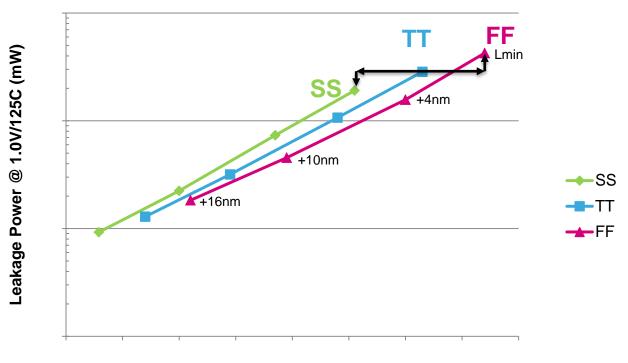




FD-SEI Process Compensation by Forward Body Bias



Performance Corner Spread w/o Body Bias 16

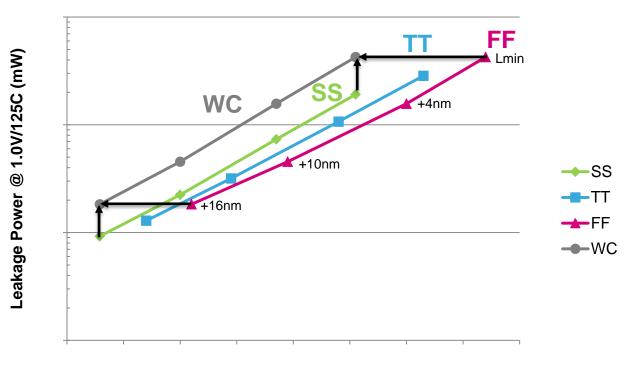


Frequency @ 0.8V/WC_temp (GHz)

 Frequency and leakage corner spreads depend on PVT and channel length

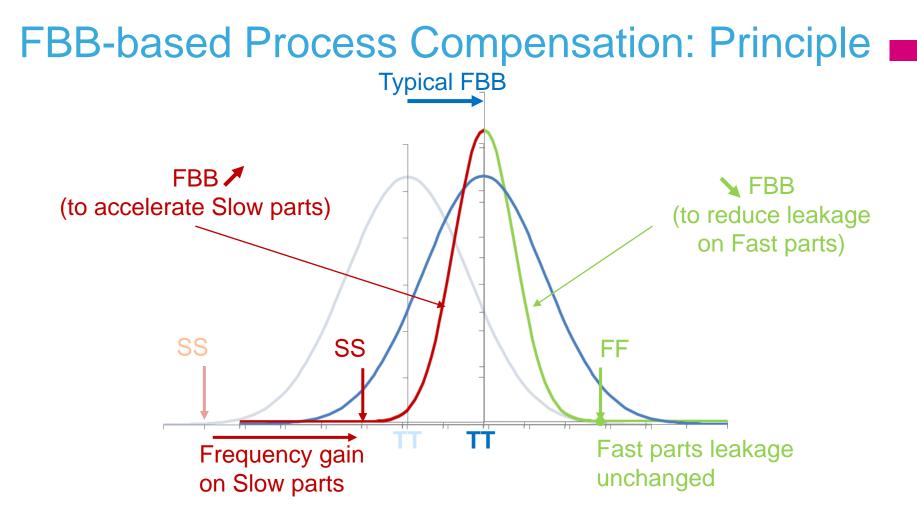


Worst Case Performances w/o Body Bias 17



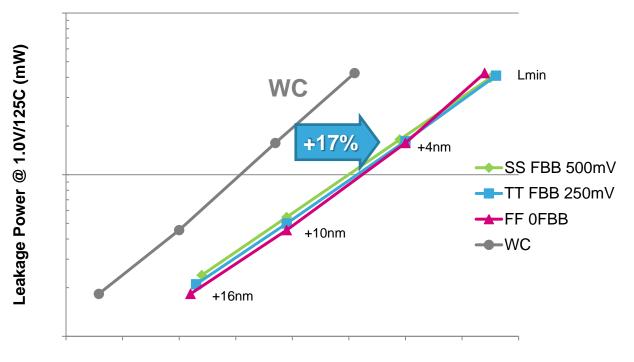
Frequency @ 0.8V/WC_temp (GHz)

- For each gate length, the worst case performance trend (WC) is built using the slowest case (SS) and the leakiest case (FF)
- This is what used for ASIC sign-off



- SLVT doesn't allow RBB → FBB must be applied on typical to allow "pseudo-RBB" for Fast parts (leakage containment)
- Higher FBB is applied to accelerate Slow parts

Process Compensation Through FBB



Frequency @ 0.8V/WC_temp (GHz)

- Process Compensation through FBB allows
 - Masking SS-FF process spread
 - Recovering +17% speed in 28nm FD-SOI, at no dynamic power expense (as it would happen if using AVS)

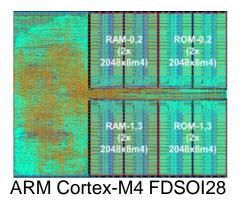


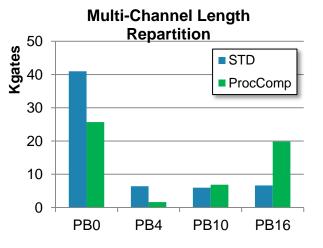
Process Compensation Benefits The case of a Cortex M4

ARM Cortex-M4

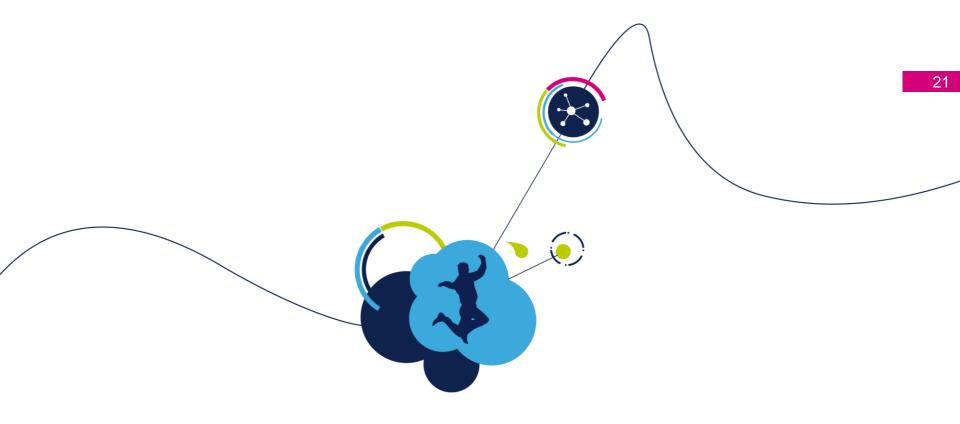
- 50kgates, 5k FF
- Target frequency: 700MHz @ WC/0.8V
- Two implementations comparison
 - Standard methodology, full process spread sign-off
 - Process compensation by FBB
 - SS corner is compensated by 600mV FBB

	Standard	Proc. Comp.	Diff/ %
Area (µm²)	81'407	61'035	-25%
Total Power @ Vmax, 125C, RCmax	REF	0.55x	-45%
Leakage (mA) @ Vmax, 125C	REF	0.49x	-51%









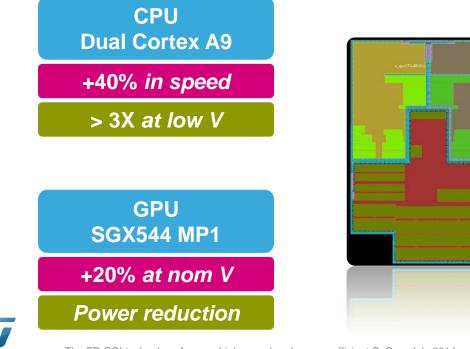
FD-SOI Technology for Fast CPU/GPU

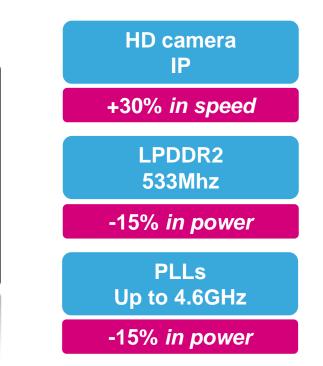


Demonstrated Reduced Design Effort for Full 28nm SoC Porting

- Same design flow as for 32/28nm LP
 - Same tools used
 - Same design cycle time
- True concurrent engineering
 - FDSOI product received before bulk version

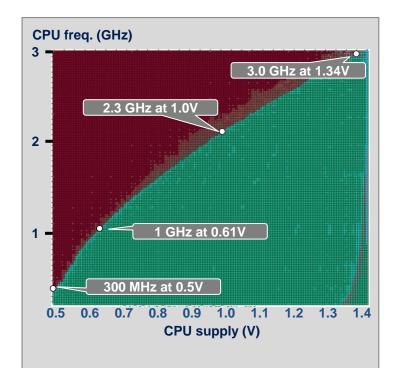
- Direct mapping of IPs + ECO
 - Script based
 - Faster than rerunning synthesis
 - Floorplan reuse





FD-SOI allowing Ultra-Wide DVFS

- FD-SOI allows the widest Vdd range for voltage scaling
- Still guaranteeing top notch speeds at very low operating voltage
 - >5x when compared to 28LP technology
 - >35% when compared to 28G technologies
- DVFS energy efficiency optimization is further extended thanks to body bias
 - Allowing to balance and optimize the static and dynamic power consumption components

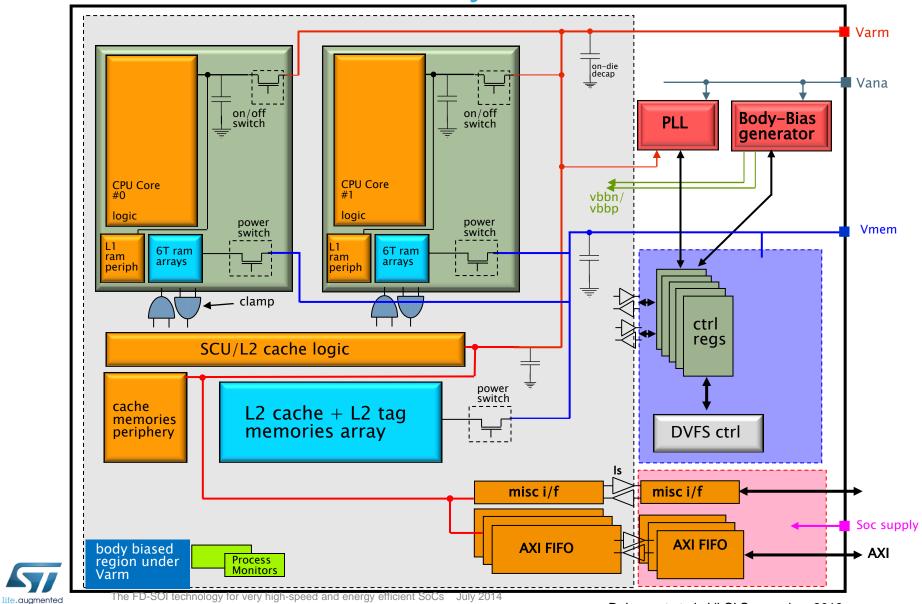


Real measurements of continuous DVFS in the range 0.5V - 1.4V

Performed on a very large number of ICs, showing extremely good reliability of the DVFS in this range



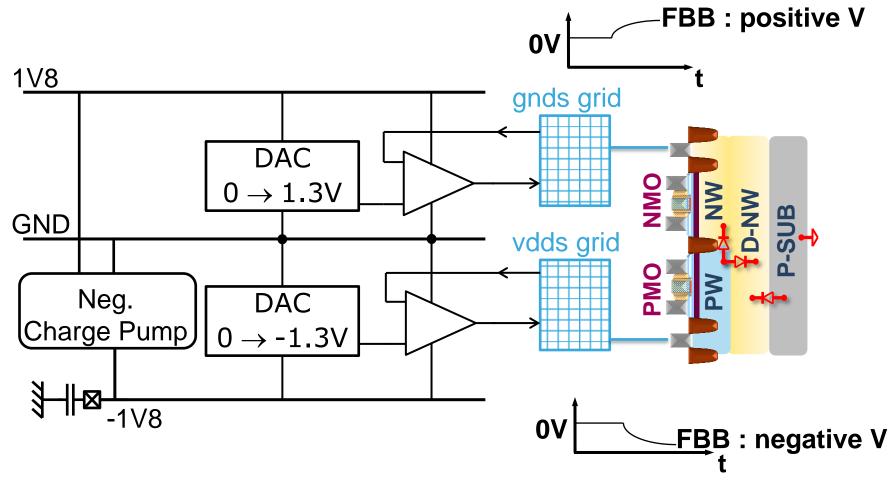
Dual Cortex A9 subsystem architecture 24



D.Jacquet et al., VLSI Symposium 2013

Body-Bias voltage generation

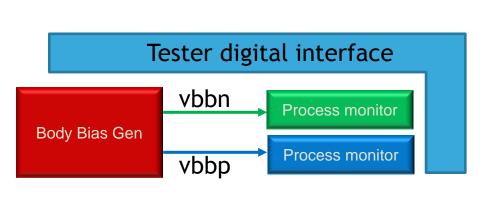
How to generate programmable body voltages ?

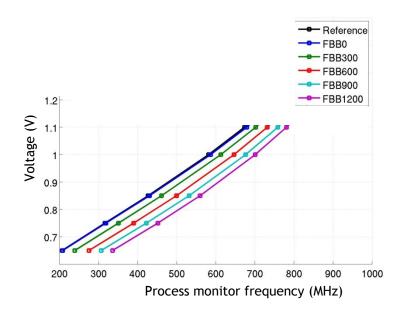




Fully digital testing of the BBgen

- The BBgen is generating 2 independent voltages
 - For the Nmos [0 to 1.3V] & Pmos [-1.3V to 0V] bodies
 - With a resolution of 100 mV
 - The embedded process monitors allow a full digital test of the BBGen in production test
 - No need for body nodes external access
 - Full access via a digital interface







Fast dynamic body-bias management

- Low Zout amplifiers allow ms settling time of the body nodes
 - E.g. 3 body domains connected to the same generator
 - Each body domain can be activated
 - In less than 1ms
 - · Activating any body domain does not disturb the voltage of the others

BB Domain#0 voltage

BB Domain#1 voltage

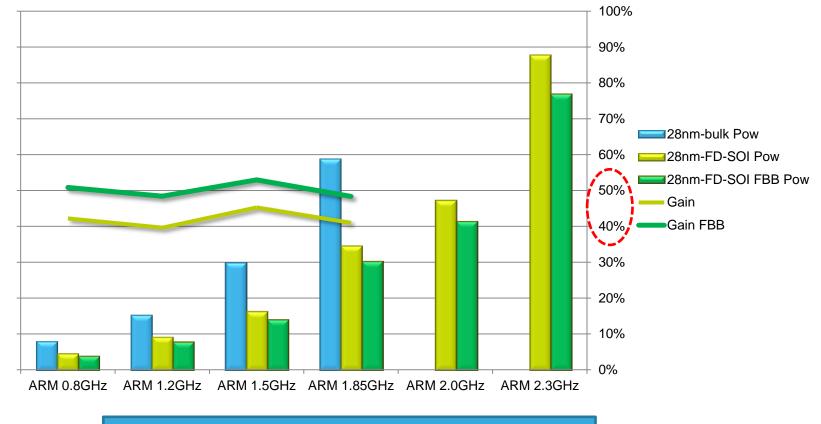
BB Domain#2 voltage

		y few mV		
	→			
	1μs			



Cortex A9 Power vs. Performances 28

A9 Single Dhrystone power consumption

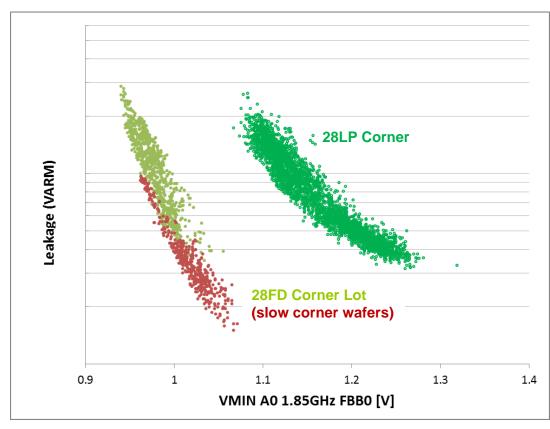


LVT only block (multi-channel: Lmin to +16nm)

Measurements done on board at room temperature



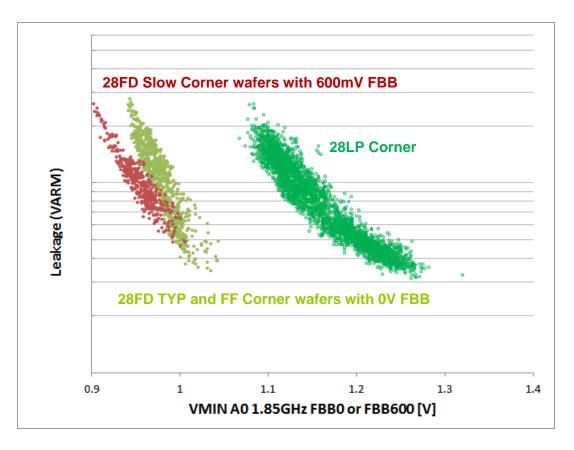
Cortex A9 Benchmark 28nm Silicon Results



- VMIN for a given frequency (1.85GHz)
 - Vmin search is an EWS metric for Fmax
 - The metric allows a one-to-one benchmark between 28FD and 28LP performances

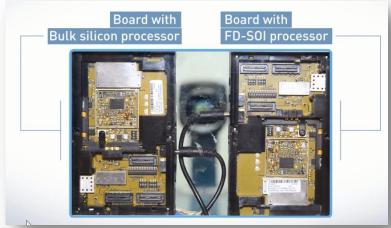


Cortex A9 Benchmark Process Compensation through FBB

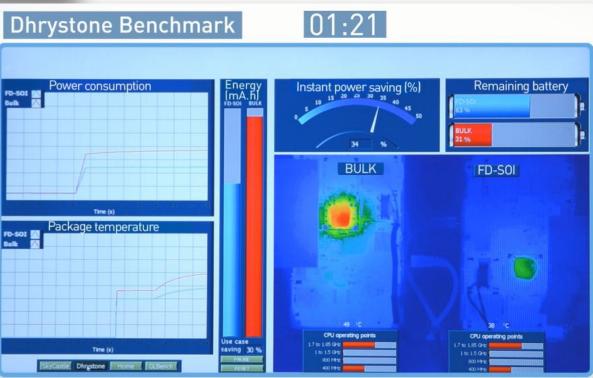


- Applying FBB 600mV enable reaching the target VMIN perfs
 - SLOW Population brought in TT-FF range

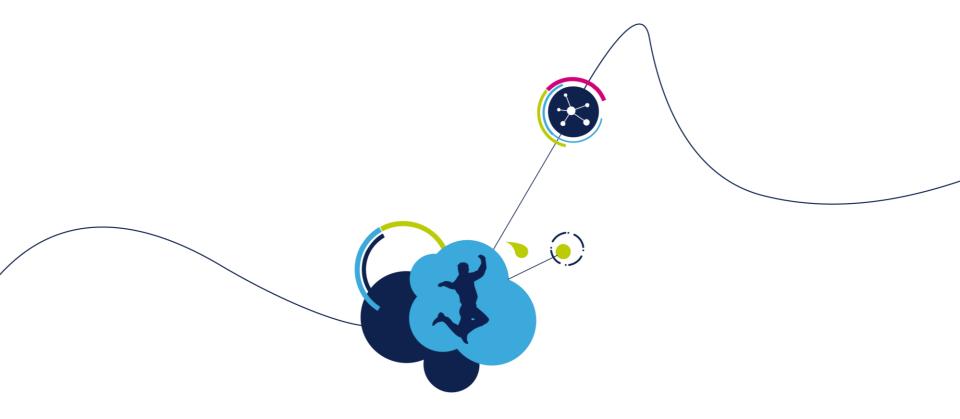




Cooler Demo







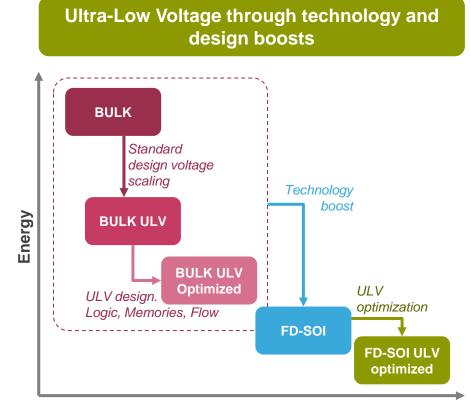
FD-SEI Technology for Ultra Low Power / Voltage applications



ULV Gains Confirmed in 28 FD-SOI

Intrinsic FD-SOI advantage for ULV

- Electrostatic control enhancement
- \rightarrow speed at low voltage
- Undoped homogeneous channel
- \rightarrow Reduced variability
- \rightarrow Lower minimum usable supply voltage
- Specific design solutions to leverage FDSOI outstanding performance at ULV
 - Higher I_{ON} for clock tree
 - FBB for improved energy efficiency and delay



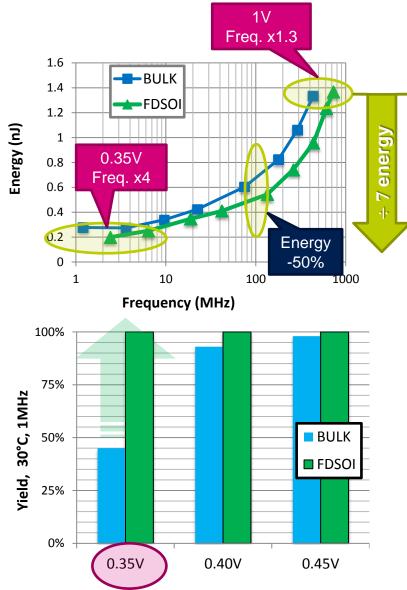
Frequency efficiency reliable



ULV Si Evidences at 28nm

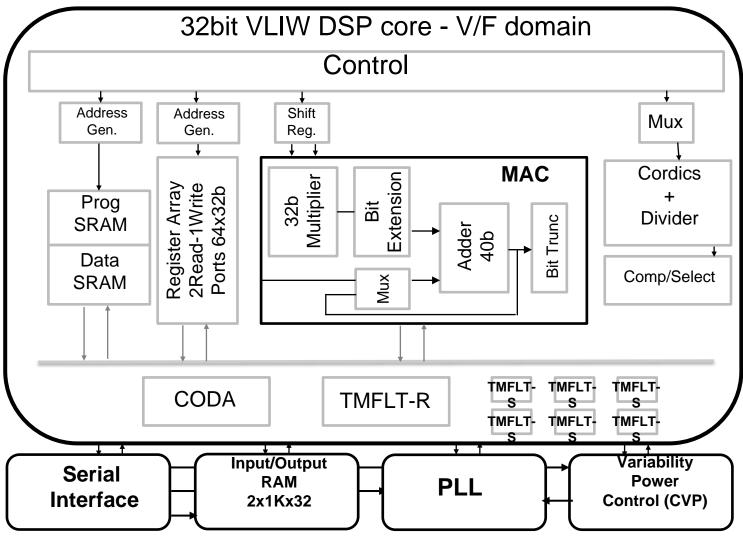
2 BCH decoders: 28FD vs. 28LP

- 252b frame error-decoder
- Both adopting ULV specific design
- FD-SOI boost at ULV
 - Ultra-wide DVFS
 - From 1 to 700 MHz for 0.35-1.00V
 - Higher frequency at given energy
 - x1.3 to x4
 - Energy saver at given frequency
 - -25% to -50%
- Yielding at lower voltages
 - FD-SOI at 100% yield already at 0.35V
 - 100mV lower than 28LP





DSP architecture



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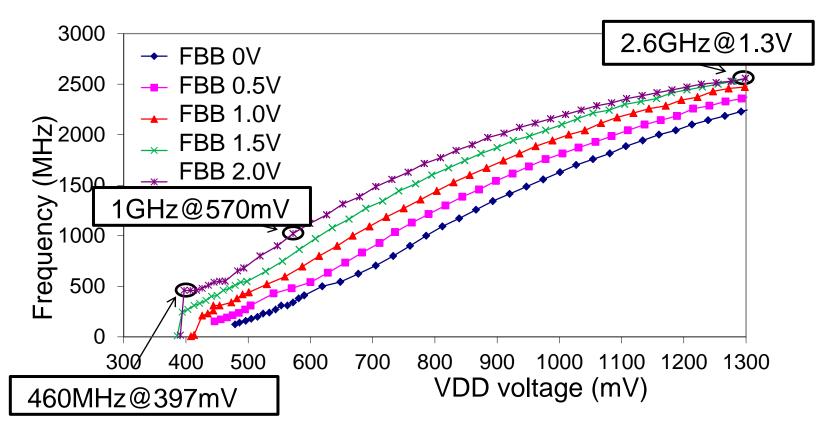
Chip Micrograph 36

UTBB FDSOI 28 nm
LVT Lmin=24nm
1 mm²
FFT 1024
0.397V-1.3V
0V/±2V



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DSP speed performance measured results 37

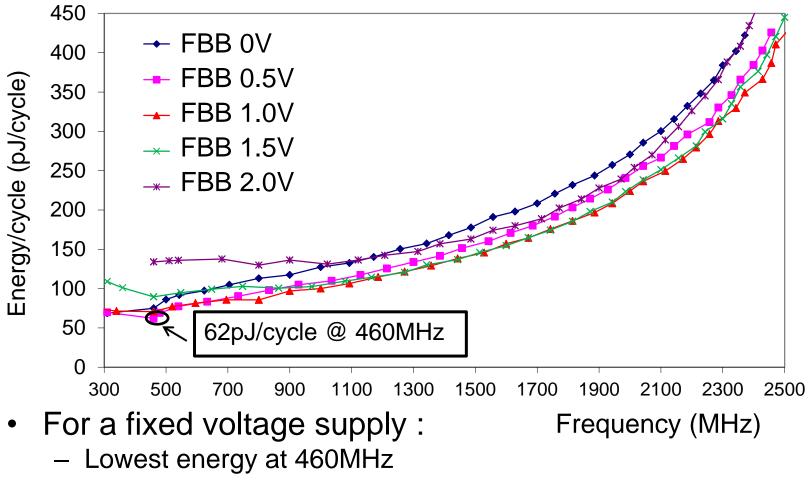


FBB up to +2V and F_{MAX} tracking : - \nearrow frequency up to 460MHz at minimum voltage

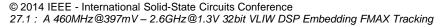


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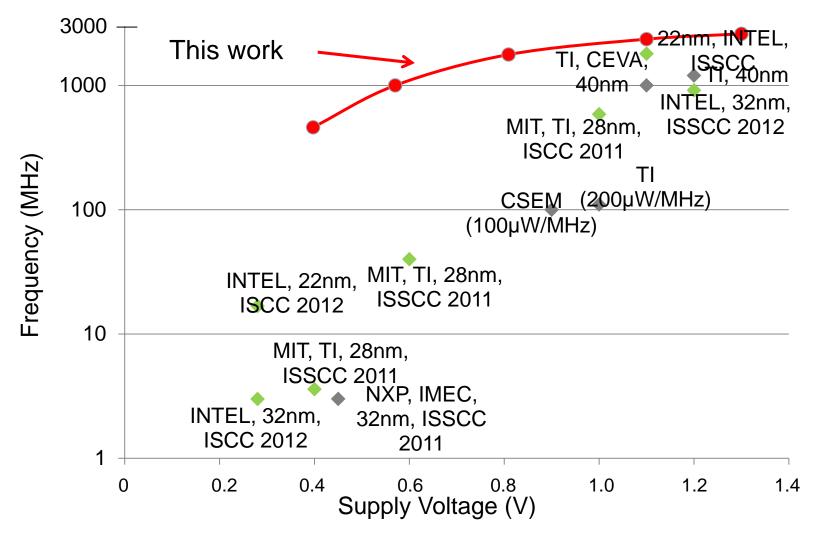
DSP energy performance measured results



Power consumption : 370mW at 1V

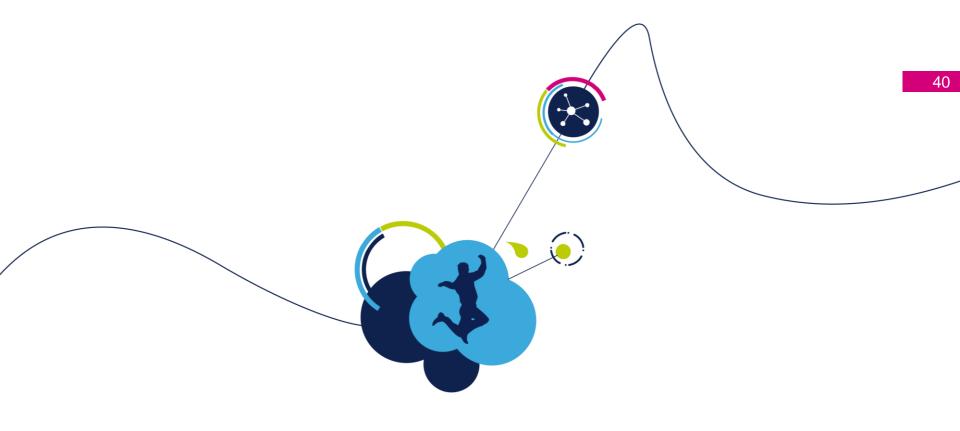


Comparison with State of the Art WVR



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Thank You!

